

Claim Amendments

1. (original) A multiple input ESD protection structure, comprising
a first p-well formed in a first n-well,
a second p-well formed in a second n-well,
an isolation ring between the n-wells and extending around the two n-wells,
a first input region formed in the first p-well,
a second input region formed in the second p-well,
a contact to the first input region,
a contact to the second input region, and
a contact to the isolation ring.
2. (original) A structure of claim 1, wherein the isolation ring is a p+ region.
3. (withdrawn) A structure of claim 1, wherein the isolation ring takes the form of two adjacent p+ rings.
4. (withdrawn) A structure of claim 3, wherein a n+ ring is formed between the p+ rings.
5. (original) A structure of claim 2, wherein the isolation ring is formed in a p-well.
6. (original) A structure of claim 5, wherein a p-buried layer (PBL) is formed below the p-well of the isolation ring.
7. (withdrawn) A structure of claim 4, wherein the p-rings are formed in a p-well.
8. (withdrawn) A structure of claim 7, wherein a p-buried layer (PBL) is formed below the p-well of the isolation ring.
9. (original) A structure of claim 1, further comprising an n-isolation region (NISO) formed beneath at least one of the n-wells.
10. (original) A structure of claim 9, further comprising a p-buried layer (PBL) formed beneath at least one of the first and second p-wells.
11. (withdrawn) A structure of claim 4, further comprising an n-isolation region (NISO) formed beneath at least one of the n-wells.

12. (withdrawn) A structure of claim 11, further comprising a p-buried layer (PBL) formed beneath at least one of the first and second p-wells.
13. (original) A structure of claim 1, wherein at least one of the first and second input regions includes a p+ region and an n+ region.
14. (withdrawn) A structure of claim 1, wherein the first input region includes only a p+ region or only a n+ region and the second input region includes both a n+ and a p+ region.
15. (withdrawn) A structure of claim 1, wherein the first input region includes only a p+ region and the second input region includes only an n+ region.
16. (withdrawn) A structure of claim 4, wherein at least one of the first and second input regions includes a p+ region and an n+ region.
17. (withdrawn) A structure of claim 4, wherein the first input region includes only a p+ region or only a n+ region and the second input region includes both a n+ and a p+ region.
18. (withdrawn) A structure of claim 4, wherein the first input region includes only a p+ region and the second input region includes only an n+ region.
19. (original) An ESD protection device that comprises
 - a first p-well formed in a first n-well,
 - a second p-well formed in a second n-well,
 - an isolation ring between the n-wells and extending around the two n wells,
 - a first input region formed in the first p-well,
 - a second input region formed in the second p-well,
 - a contact to the first input region,
 - a contact to the second input region, and
 - a contact to the isolation ring, wherein the isolation ring is connected to ground or is biased to a predefined voltage.
20. (withdrawn) A multiple input ESD protection structure, comprising
 - a first p-well formed in a first n-well,
 - a second p-well formed in a second n-well,
 - a first input region formed in the first p-well,

a second input region formed in the second p-well,

a contact to the first input region, and

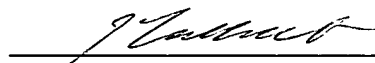
a contact to the second input region, wherein one of the input regions is connected to ground and forms at least a partial isolation ring around the other input region.

Election:

Applicant elects the claims relating to embodiment shown in Figure 3.
These include claims 1, 2, 5, 6, 9, 10, 13, 19.

pectfully Submitted,

Dated: 7/9/, 2005



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